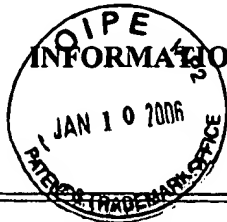


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DPP:iar 01/04/06 1011-54375-01 469545 109-013



**INFORMATION DISCLOSURE STATEMENT
BY APPLICANT**

Attorney Docket Number	1011-54375-01
Application Number	09/620,021
Filing Date	July 20, 2000
First Named Inventor	Rajski
Art Unit	2133
Examiner Name	Phung M. Chung

U.S. PATENT DOCUMENTS

Copies of U.S. Patent documents do not need to be provided, unless requested by the Patent and Trademark Office. For patents, provide the patent number and the issue date. For published U.S. applications, provide the publication number and the publication date. For unpublished pending patent applications, provide the application number and the filing date.

Examiner's Initials*	Cite No. (optional)	Number	Publication Date	Name of Applicant or Patentee
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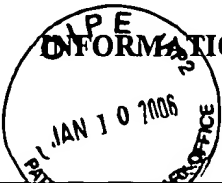
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EXAMINER SIGNATURE: /Phung Chung/	DATE CONSIDERED: 06/27/2006
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* Examiner: Initial if reference considered, whether or not in conformance with MPEP 609. Draw line through cite if not in conformance and not considered. Include copy of this form with next communication to applicant.

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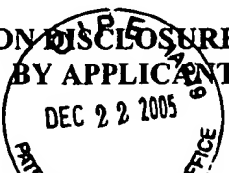
	Attorney Docket Number	1011-54375-01
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DPP/PMB:iar 12/13/05 1011-54375-01 109-013

INFORMATION DISCLOSURE STATEMENT BY APPLICANT 	Attorney Docket Number	1011-54375-01
	Application Number	09/620,021
	Filing Date	July 20, 2000
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	Examiner Name	Phung M. Chung

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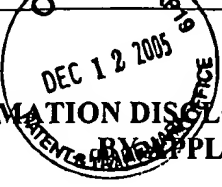
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